

Notice of References Cited	Application/Control No. 10/796,599	Applicant(s)/Patent Under Reexamination FENG, WEISHI	
	Examiner Martin Jeriko P. San Juan	Art Unit 2132	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0034785 A1	02-2004	Tai et al.	713/189
*	B	US-5,999,629	12-1999	Heer et al.	705/51
	C	US-			
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	I	US-			
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	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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